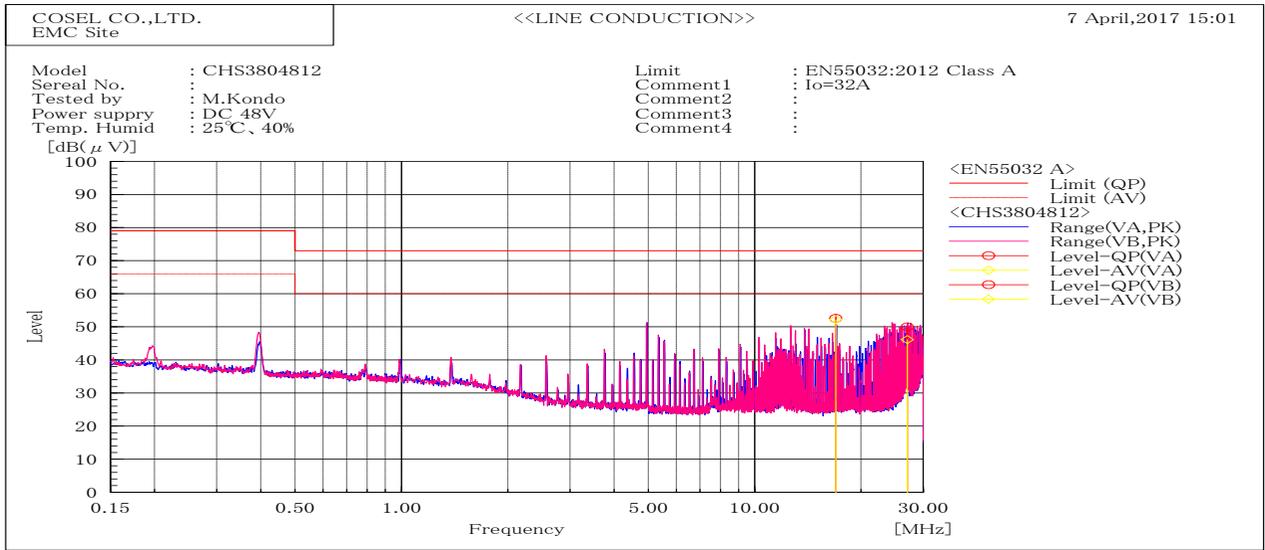
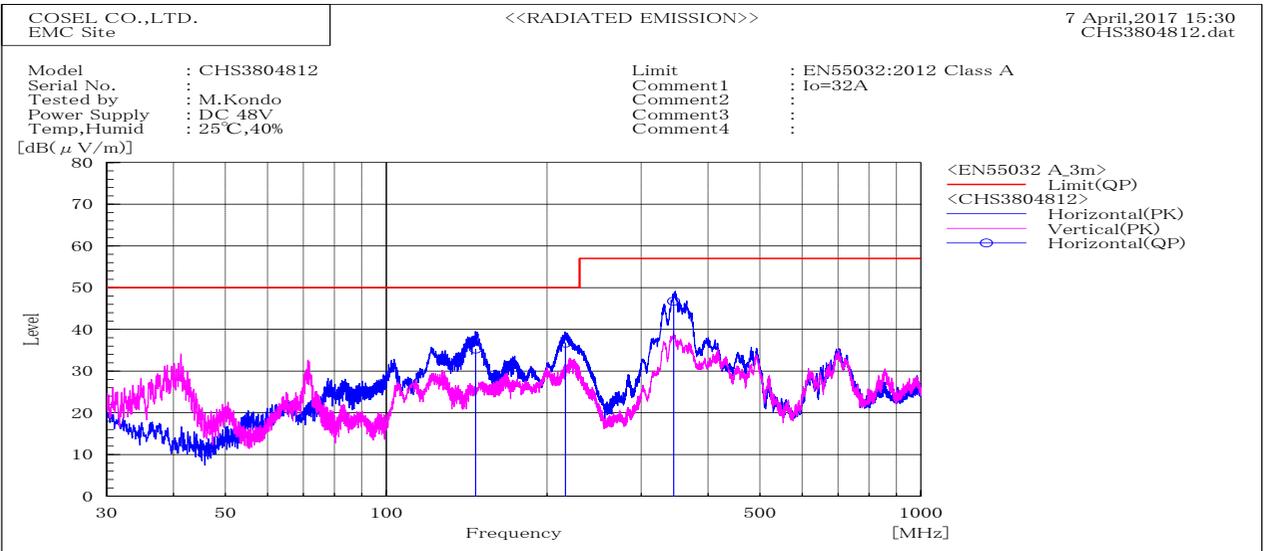


DATA SHEET		Date	07-Apr-17
Model	CHS3804812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo



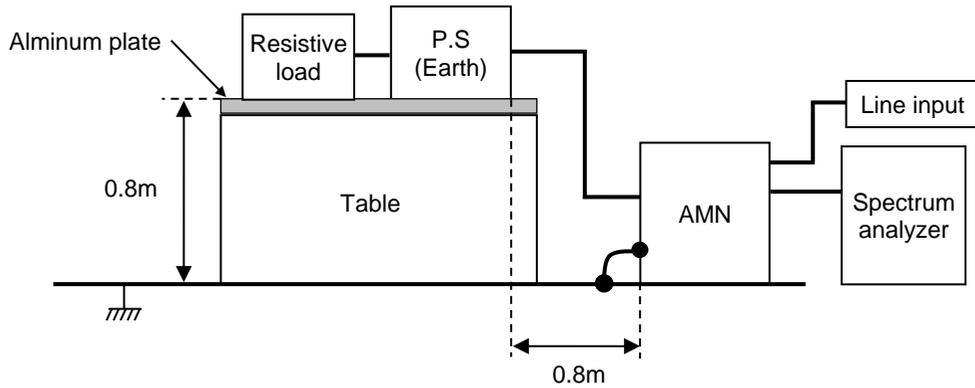
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
16.9752	VB	52.5	52.2	73	60	20.5	7.8	Pass	
27.0503	VA	50	46.1	73	60	23	13.9	Pass	



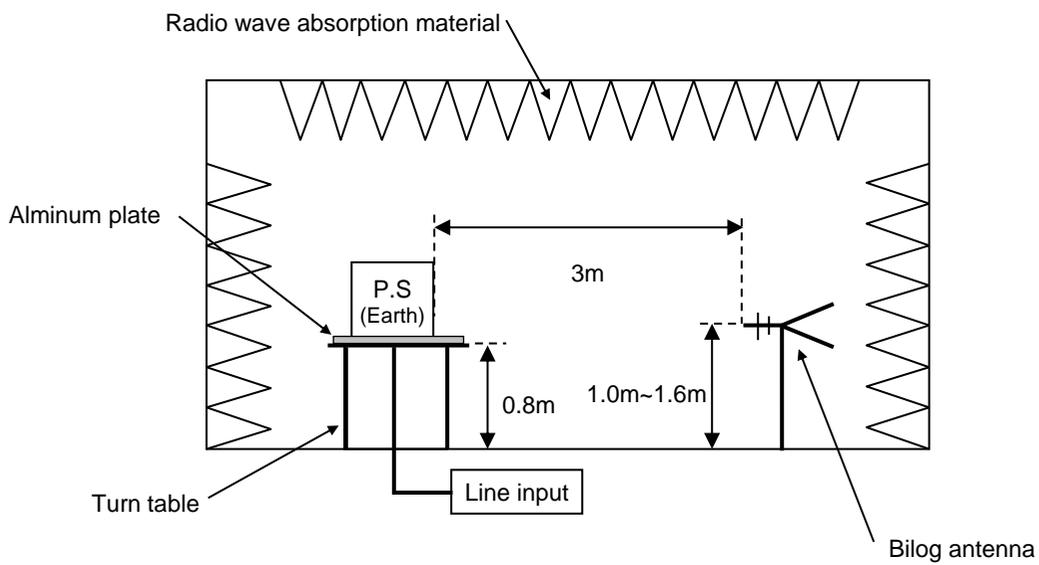
Frequency MHz	Polarization	Stability	Reading dB(uV)	Limit dB(uV/m)	Margin dB(uV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
146.906	H	Stable	35.3	50.0	14.7	Pass	140	310	
216.362	H	Stable	36.7	50.0	13.3	Pass	113	237	
344.713	H	Stable	46.7	57.0	10.3	Pass	114	194	

DATA SHEET		Date	07-Apr-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Kondo

1. Line conduction



2. Radiated emission



Conditions

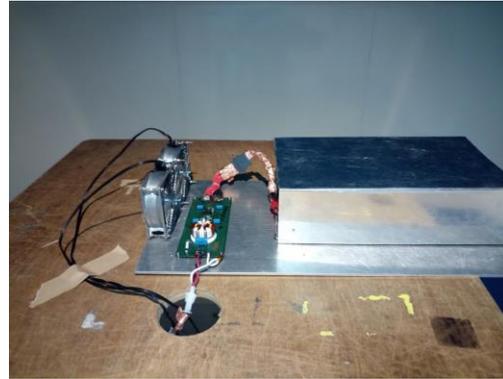
Test : EMI
 Model Name : CHS380 Series

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

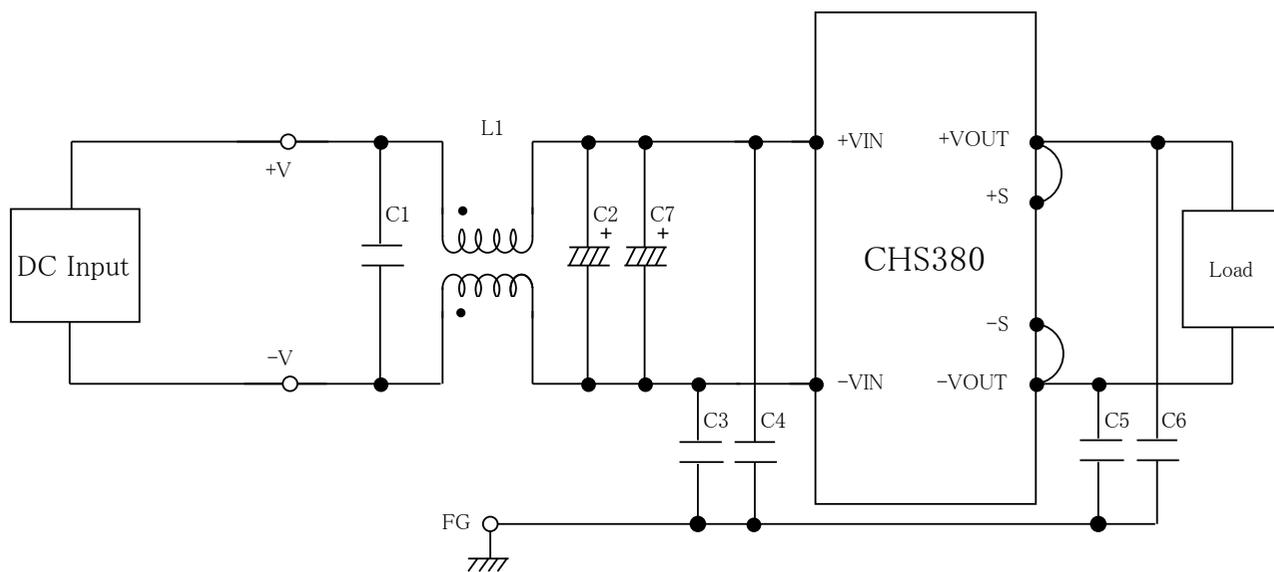


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C7 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4(NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4(NITSUKO)